

**Search Notes**

Application/Control No.

10/541,327

Examiner

Nguyen N. Hanh

Applicant(s)/Patent under  
Reexamination

SHIMIZU ET AL.

Art Unit

2834

**SEARCHED**

Class	Subclass	Date	Examiner
310	156.01- 156.84	6/20/2006	HN
310	261	6/20/2006	HN
310	262	6/20/2006	HN
310	218	6/20/2006	HN
update	All	12/14/06	HN
Search			

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR